

Notice of References Cited	Application/Control No. 10/635,649	Applicant(s)/Patent Under Reexamination HATADE ET AL.	
	Examiner VAN T. PHAM	Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,728,193	04-2004	Uchizaki et al.	369/112.01
*	B	US-2001/0000310	04-2001	Yoo et al.	369/112.26
	C	US-			
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	I	US-			
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	K	US-			
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	M	US-			

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	N	JP 10-021574 Traslation	01-1998	Japan	Konayama Shiyuuichi	
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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